



Applications and Analysis Strategy of XPS on Surface Characterization

XPS表面分析之應用與分析技術

Host: Instrument Center, College of Science

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Language: English

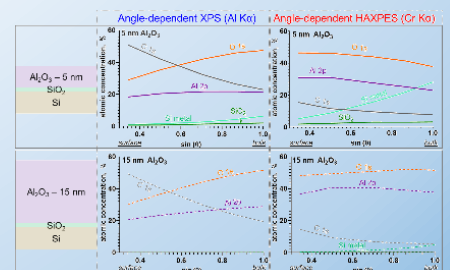
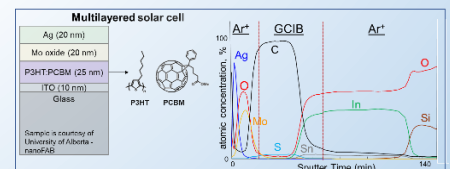
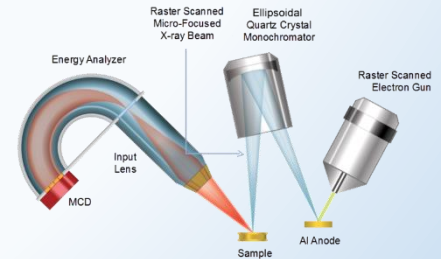
語言：英文

Location: Chemistry Building A210

演講地點：積學館A210室

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This workshop aim to introduce various advanced XPS analysis strategies to assist researcher to conduct surface characterization. In this lecture, we will include general XPS measurement, scanning method, angle-resolved method, depth profiling method, mapping and hard X-ray method as well as its data analysis.

本次研討會將介紹不同種類的XPS技術與表面分析策略來幫助研究人員選用適當的分析方法進行表面分析。其中我們將會介紹一般性分析方法、掃描式、角度解析式、縱深分析、影像分析以及高能X-ray分析法以及相關的數據分析。